

**Search Notes**

Application/Control No.

10/600,014

Examiner

Shew-Fen Lin

Applicant(s)/Patent under  
Reexamination

CHATTERJEE ET AL.

Art Unit

2166

**SEARCHED**

Class	Subclass	Date	Examiner
715	512	10/12/2006	SFL
715	730	10/12/2006	SFL
707	100	10/12/2006	SFL
709	200-250	10/12/2006	SFL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Google	10/12/2006	SFL
East (US-PUB, USPAT, USOCR, EPO, JPO, IBM-TDB	10/12/2006	SFL